#### Optical Links for the ATLAS SCT and Pixel Detector



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Ingrid-Maria Gregor (University Wuppertal) for the ATLAS collaboration



Ingrid-Maria Gregor

University of Wuppertal

ATLAS Inner Detector
Optical Link Architecture
System Tests
Conclusion



#### **ATLAS Inner Detector**

Ingrid-Maria Gregor





### Data Transfer

- Control and clock information must be transferred from acquisition system to the silicon detectors
- Hit data must be transferred from the modules to a remote acquisition system
- use of copper links unfeasible
  - large amount of dead material which would be introduced
  - problems from cross-talk and ground loops
- it is proposed to use custom optical links to transfer data to and from the detector modules (SCT and Pixel Detector)



# Special Requirements (1)

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#### radiation hardness

ionizing radiation : 100kGy (SCT) to 550kGy (Pixel detector)

#### > 1 billion lung x-rays

- $\succ$  neutron radiation :
  - Si-devices: 1\*10<sup>15</sup> n(1MeV)/cm<sup>2</sup>
  - > GaAs-devices: up to 6.4\*10<sup>15</sup> n(1MeV)/cm<sup>2</sup>
- > expected over the 10 year lifetime of ATLAS (1<sup>st</sup> layer)



# Special Requirements (2)

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#### low mass

- additional interactions in non-instrumented regions of the detector would compromise the quality of momentum measurements
- particle conversion







driver chip for VCSEL on acquisition side (12 way)
 40MHz-Clock and Commands on one link



# TTC Link

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University of Wuppertal

# DORIC

- ► <u>Digital Optical Receiver IC</u>
- decodes the signals received by the PIN
  - recovers commands and 40MHz-clock
  - LVDS output
- 2 versions: bipolar (SCT) and CMOS (Pixel)
- SCT redundancy system: TTC data can be taken from redundancy link from a neighbouring data

## Data Link

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VDC

- ► <u>V</u>CSEL <u>D</u>river <u>C</u>hip
- LVDS input
  - 40Mbit/s (SCT), 80Mbit/s (Pixel 1st and 2nd layer) or 160Mbit/s (B-layer)
- ► NRZ (20MHz = 40Mbit/s)
- 2 versions: bipolar (SCT) and CMOS (Pixel)
- SCT: in the event of failure, the data can be rerouted through the second link
- Pixel: one link for outer layers, two for B-layer (160MBit/sec)



# Opto-Package Specs

- Custom package made of material with low Z, non-magnetic, with 2 VCSELs and 1 PIN
   Fibres attached without standard connector
- not larger than 5.5 mm x 5.5 mm x 1.6 mm
- package and including devices have to stand radiation levels
- operation temperature during testing: -25°C to 40°C
- operation temperature during ATLAS: -25°C to 15°C
- three different designs under survey



# Taiwan Opto-Package

Ingrid-Maria Gregor





# Taiwan Opto-Package

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5.5 mm



# Taiwan Opto-Package

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# **Opto-Elbow (Pixel)**





# Opto Package Support (SCT)





## System Tests

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Characteristics of opto-link for this system under test:
 Radiation and Annealing studies
 Lifetime studies
 Bit Error Rate
 Single Event Upsets



# Annealing Studies of VCSEL

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### VCSEL tests

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VCSELs were not powered during irradiation
 radiation induced damages can be annealed up to 90% over a period of days/weeks
 results suggest brief 20 mA current annealing sessions
 following aging tests showed an expected lifetime of a few hundred years (irradiated)
 further irradiation and lifetime tests are under way (up to Pixel level of 6.4\*10<sup>15</sup> n(1MeV)/cm2)



# Bit Error Rate (BER)

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BER: good parameter to evaluate the performance of the optolink

$$BER = \frac{N_{error}}{N_{bits}} < 10^{-9}$$



Good results with SCT link
Pixel test under way



# Single Event Upsets

- Single Event Upsets caused by a very high energy deposition in a small volume of electronics chips
   most sensitive region: reverse-biased p/n junction where high electric field is very effective in collecting the charge by drift
- PIN = reverse biased p/n junction
- 100μm x 50μm x 50μm !
- First SEU appearance : NPL neutron beam
- test with pions at PSI



#### SEU at PSI

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## Conclusion

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data transfer using optical links
 custom packaging developments for the 40 Mb/s optical link show good physical results
 design of complete Pixel opto-link under way
 radiation induced damages can be annealed up to 90% over a period of days
 results suggest brief 20 mA current annealing sessions
 SEU problems can be fixed by sending more light



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### http://www.atlas.uni-wuppertal.de/ Optolink/Pix\_Optolink.html

